

<b>Notice of References Cited</b>		Application/Control No. 10/588,109	Applicant(s)/Patent Under Reexamination OKADA ET AL.	
		Examiner DUC M. NGUYEN	Art Unit 2618	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0057750	05-2002	Nakao et al.	375/345
*	B US-2004/0097212	05-2004	Matsumoto et al.	455/296
*	C US-6,400,932	06-2002	Oh et al.	455/150.1
*	D US-6,593,803	07-2003	Yoshizawa, Atsushi	327/553
*	E US-5,726,599	03-1998	Genest, Pierre	327/553
*	F US-6,388,510	05-2002	Hayashi et al.	327/552
*	G US-5,572,163	11-1996	Kimura et al.	327/553
*	H US-5,760,702	06-1998	Ito et al.	340/825.2
*	I US-6,778,023	08-2004	Christensen, Kaare Tais	331/16
*	J US-6,107,870	08-2000	Kawano, Mitsumo	327/553
*	K US-5,745,001	04-1998	Ueshima et al.	327/553
*	L US-6,169,751	01-2001	Shirakata et al.	370/480
*	M US-2008/0169948	07-2008	Okamoto et al.	341/118

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2003-188683	07-2003	JP	Hasegawa	H03H 11/04
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.